



### P-CHANNEL ENHANCEMENT MODE MOSFET

LD-MOS Technology with the Lowest Figure of Merit:  $R_{DS(on)} = 28m\Omega$  to Minimize On-State Losses

Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)

Source

Halogen and Antimony Free. "Green" Device (Note 3)

Qualified to AEC-Q101 Standards for High Reliability

Q<sub>g</sub> = 5.4nC for Ultra-Fast Switching Vgs(th) = -0.6V typ. for a Low Turn-On Potential

Terminal Connections: See Diagram Below

Weight: 0.0018 grams (Approximate)

CSP with Footprint 1.5mm × 1.5mm

Height = 0.62mm for Low Profile ESD = 3kV HBM Protection of Gate

## Product Summary (Typ. @ V<sub>GS</sub> = -4.5V, T<sub>A</sub> = +25°C)

Ī	V <sub>DSS</sub>	R <sub>DS(on)</sub>	Qg	Q <sub>gd</sub>	ID	
	-20V	28mΩ	5.4nC	1.5nC	-5.8A	

## **Description and Applications**

This new generation MOSFET is designed to minimize the onstate resistance (R<sub>DS(on)</sub>) and yet maintain superior switching performance, making it ideal for high-efficiency power management applications.

## Applications

- Battery Management
- Load Switch
- **Battery Protection**



#### G D S S D D S S D Equivalent Circuit Top-View Pin Configuration

**Mechanical Data** Case: U-WLB1515-9

**Features and Benefits** 

## Ordering Information (Note 4)

Part Number	Case	Packaging
DMP2033UCB9-7	U-WLB1515-9	3,000/Tape & Reel

1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant. Notes:

2. See http://www.diodes.com for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.

3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.</li>
4. For packaging details, go to our website at http://www.diodes.com.

## **Marking Information**



AW = Product Type Marking Code YM = Date Code Marking Y = Year (ex: Y = 2011)M = Month (ex: 9 = September)

Date Code Key												
Year	2011 2012 2013		20	2014			2016	2	2017			
Code	Y		Z		А	E	3	С		D		E
Month	Jan	Feb	Mar	Apr	Мау	Jun	Jul	Aug	Sep	Oct	Nov	Dec
Code	1	2	3	4	5	6	7	8	9	0	N	D



# Maximum Ratings (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic		Symbol	Value	Units	
Drain-Source Voltage		V <sub>DSS</sub>	-20	V	
Gate-Source Voltage		V <sub>GSS</sub>	-6	V	
Continuous Drain Current (Note 5) $V_{GS}$ = -4.5V	Steady State	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	ID	-4.2A -3.3A	А
Continuous Drain Current (Note 6) $V_{GS}$ = -4.5V	Steady State	ID	-5.8A -4.5A	А	
Pulsed Drain Current		I <sub>DM</sub>	-30	А	

## Thermal Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Units
Total Power Dissipation (Note 5)	PD	1.0	W
Total Power Dissipation (Note 6)	PD	1.8	W
Thermal Resistance, Junction to Ambient (Note 5)	R <sub>0JA</sub>	126.8	°C/W
Thermal Resistance, Junction to Ambient (Note 6)	R <sub>0</sub> JA	69	°C/W
Operating and Storage Temperature Range	TJ, TSTG	-55 to +150	°C

## Electrical Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition		
OFF CHARACTERISTICS (Note 7)								
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-20	-	-	V	$V_{GS} = 0V, I_D = -250\mu A$		
Gate-Source Breakdown Voltage	BV <sub>GSS</sub>	-6.1	-	-	V	$I_{GS} = -250 \mu A, V_{DS} = 0 V$		
Zero Gate Voltage Drain Current @Tc = +25°C	IDSS	-	-	-1	μA	$V_{DS} = -16V, V_{GS} = 0V$		
Gate-Source Leakage	IGSS	-	-	-100	nA	$V_{GS} = -6V, V_{DS} = 0V$		
ON CHARACTERISTICS (Note 7)								
Gate Threshold Voltage	V <sub>GS(th)</sub>	-0.4	-0.6	-1.1	V	$V_{DS} = V_{GS}, I_D = -250 \mu A$		
			28	33		$V_{GS} = -4.5V, I_D = -2A$		
Static Drain-Source On-Resistance	R <sub>DS</sub> (ON)	-	35	45	mΩ	$V_{GS} = -2.5V, I_D = -2A$		
			45	65		$V_{GS} = -1.8V, I_D = -2A$		
Forward Transfer Admittance	Y <sub>fs</sub>	-	10.8	-	S	$V_{DS} = -10V, I_D = -2A$		
Diode Forward Voltage (Note 6)	V <sub>SD</sub>	-	-0.7	-1	V	$V_{GS} = 0V, I_S = -2A$		
Reverse Recovery Charge	Qrr	-	15	-	nC	V <sub>dd</sub> = -9.5V, I <sub>F</sub> = -2A,		
Reverse Recovery Time	t <sub>rr</sub>	-	25	-	ns	di/dt = 200A/µs		
DYNAMIC CHARACTERISTICS (Note 8)								
Input Capacitance	Ciss	-	382	500	pF			
Output Capacitance	Coss	-	204	270	pF	− V <sub>DS</sub> = -10V, V <sub>GS</sub> = 0V, − f = 1.0MHz		
Reverse Transfer Capacitance	C <sub>rss</sub>	-	86	115	pF	1 - 1.00012		
Series Gate Resistance	R <sub>G</sub>		26.1	35	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$		
Total Gate Charge (4.5V)	Qg	-	5.4	7.0	nC			
Gate-Source Charge	Q <sub>gs</sub>	-	0.7	-	nC	$V_{GS} = -4.5V, V_{DS} = -10V,$		
Gate-Drain Charge	Q <sub>gd</sub>	-	1.5	-	nC	$I_D = -2A$		
Turn-On Delay Time	t <sub>D(on)</sub>	-	8.5	-	ns			
Turn-On Rise Time	tr	-	11.8	-	ns	$V_{DD} = -10V, V_{GS} = -4.5V,$		
Turn-Off Delay Time	t <sub>D(off)</sub>	-	47	-	ns	$I_{DS} = -2A, R_G = 2\Omega,$		
Turn-Off Fall Time	t <sub>f</sub>	-	56	-	ns	]		

Notes: 5. Device mounted on FR-4 PCB with minimum recommended pad layout.

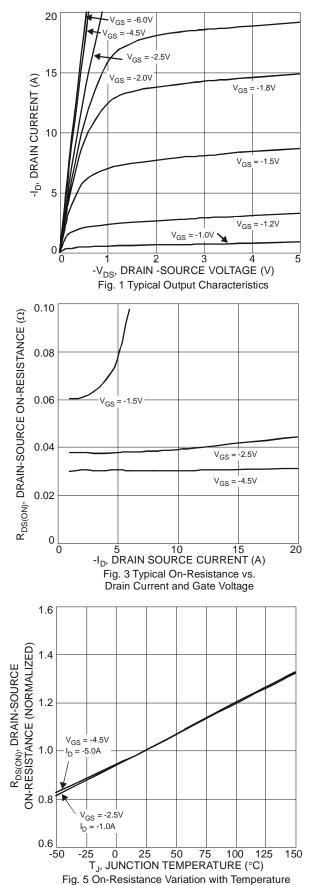
6. Device mounted on FR4 material with 1-inch<sup>2</sup> (6.45-cm<sup>2</sup>), 2-oz. (0.071-mm thick) Cu.

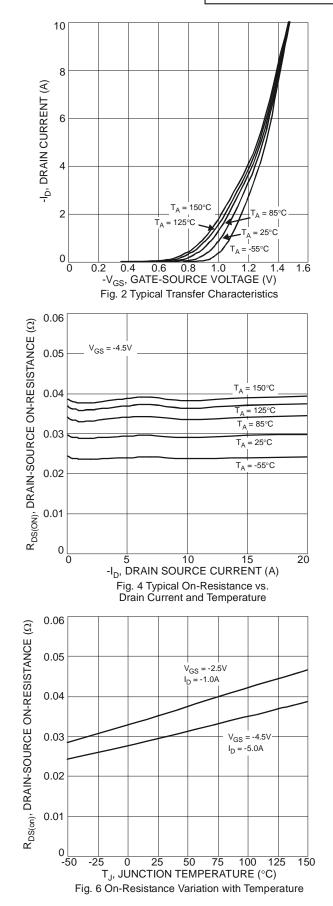
7. Short duration pulse test used to minimize self-heating effect.

8. Guaranteed by design. Not subject to production testing.

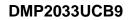


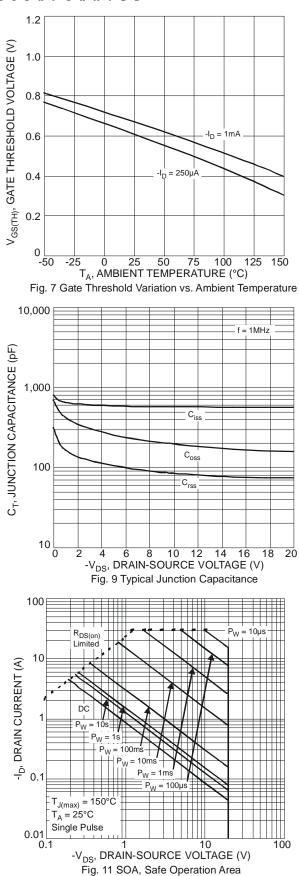


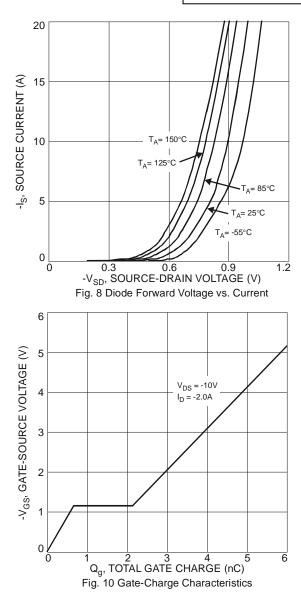




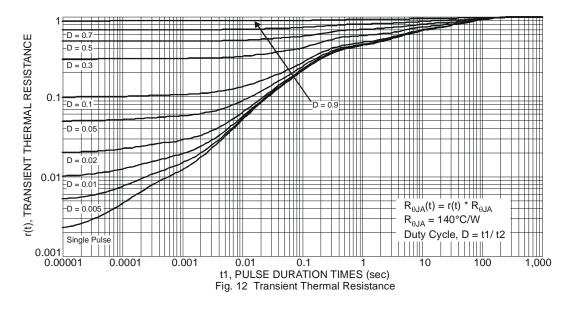






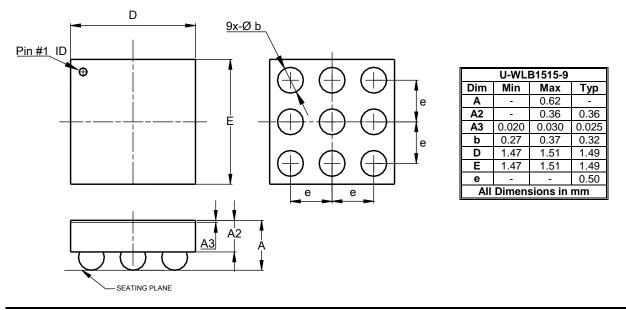






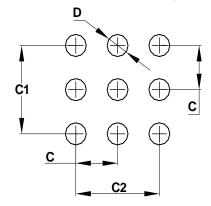
## Package Outline Dimensions

Please see AP02001 at http://www.diodes.com/\_files/datasheets/ap02001.pdf for the latest version.



## **Suggested Pad Layout**

Please see AP02001 at http://www.diodes.com/\_files/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)				
С	0.50				
C1	1.00				
C2	1.00				
D	0.25				



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